

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/612,129 <b>Examiner</b> Phat X. Cao	<b>Applicant(s)/Patent under Reexamination</b> YEW ET AL. <b>Art Unit</b> 2814	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
257	668	12/20/2005	PC	EAST: IS&R and BRS	12/20/2005	PC
257	783	12/20/2005	PC			
<b>INTERFERENCE SEARCHED</b>				<b> </b>		
Class	Subclass	Date	Examiner			
257	668	12/20/2005	PC			
257	783	12/20/2005	PC			
USPGPUB - text search (see print out)		12/20/2005	PC			